

(19) United States

(12) Patent Application Publication (10) Pub. No.: US 2024/0179899 A1

May 30, 2024 (43) **Pub. Date:**

(54) NAND FLASH DEVICE

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Appl. No.: 18/514,158

Filed: (22)Nov. 20, 2023

(30)Foreign Application Priority Data

Nov. 30, 2022 (KR) 10-2022-0165103

Publication Classification

(51)	Int. Cl.	
	H10B 41/41	(2006.01)
	G11C 16/04	(2006.01)
	H10B 41/10	(2006.01)
	H10B 41/27	(2006.01)

H10B 41/35	(2006.01)
H10B 43/10	(2006.01)
H10B 43/27	(2006.01)
H10B 43/35	(2006.01)
H10B 43/40	(2006.01)

(52) U.S. Cl.

H10B 41/41 (2023.02); G11C 16/0483 CPC (2013.01); H10B 41/10 (2023.02); H10B 41/27 (2023.02); H10B 41/35 (2023.02); Hì0B 43/10 (2023.02); Hì0B 43/27 (2023.02); H10B 43/35 (2023.02); H10B 43/40 (2023.02)

(57)**ABSTRACT**

A NAND flash device may include a peripheral circuit including a transistor, a substrate, and a device isolation region defining an active region of the substrate. The transistor may include a first gate structure on the active region. The transistor may include source and drain regions extending in a first direction in the active region on both sides of the first gate structure, which may include a first lightlydoped source and drain region adjacent to the first gate structure and a second lightly-doped source and drain region integrally connected thereto. The second lightly-doped source and drain region may be arranged farther from the first gate structure than the first lightly-doped source and drain region. The second lightly-doped source and drain region may have a smaller width in the second direction than a width of the first lightly-doped source and drain region in the second direction.

